

FCC PART 15 CLASS B MEASUREMENT AND TEST REPORT

For

ZTE Corporation

ZTE Plaza, Hi-tech Park, Nanshan District, Shenzhen, Guangdong, China 518057

FCC ID: Q78-ZTEC321 Model: ZTE C321

Report Type:		Product Type:	
🖂 Original Report		800MHz CDMA 1X Digital Mobile Phone	
	Guan Bin g	uan bin	
Test Engineer:	Bob Xiong	uan bin Into Xing	
Report No.:	RZTE0805213-1		
Test Date: 2008-05-15 to 200		08-05-27	
Report Date:	2008-05-28		
Reviewed By:	Lab Manager Xie yuming	Xie Yuming	
Prepared By:	ZTE Corporation Reliability Testing Center ZTE Plaza, Keji Road South, Hi-Tech Industrial Park, NanShan District, Shenzhen, Guangdong 518057, P.R. of China Tel: +86-755-26770345 Fax: +86-755-26770347		

ZTE中兴 ZTE Corporation

TABLE OF CONTENTS

1	GE	ENERAL DESCRIPTION	
	1.1	PRODUCT DESCRIPTION FOR EQUIPMENT UNDER TEST (EUT)	3
	1.2	ЕИТ Рното	3
	1.3	Objective	
	1.4	RELATED SUBMITTAL(S)/GRANT(S)	
	1.5	TEST METHODOLOGY	
	1.6	Test Facility	4
2	SY	STEM TEST CONFIGURATION	5
	2.1	JUSTIFICATION	5
	2.2	EQUIPMENT MODIFICATIONS	
	2.3	LOCAL SUPPORT EQUIPMENT LIST AND DETAILS	
	2.4	Test Setup Block Diagram	
3	SU	IMMARY OF TEST RESULTS	6
4	FC	CC §15.107 - CONDUCTED EMISSIONS	7
	4.1	APPLICABLE STANDARD	7
	4.1	.1 AS PER FCC §15.107: CONDUCTED LIMITS	
	4.2	EUT SETUP	7
	4.3	TEST EQUIPMENT LIST AND DETAILS	8
	4.4	Test Procedure	
	4.5	Environmental Conditions	
	4.6	SUMMARY OF TEST RESULTS	9
	4.7	CONDUCTED EMISSIONS TEST PLOTS	
5	FC	C §15.109 – RADIATED EMISSIONS	
	5.1	APPLICABLE STANDARD	
	5.2	TEST SETUP	11
	5.2 5.3	TEST SETUP TEST EQUIPMENT LIST AND DETAILS	11 12
	5.2 5.3 5.4	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE	11 12 12
	5.2 5.3 5.4 5.5	Test Setup Test Equipment List and Details Test Procedure Environmental Conditions	11 12 12 12
	5.2 5.3 5.4 5.5 5.6	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION	11 12 12 12 13
	5.2 5.3 5.4 5.5 5.6 5.7	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHz TO 1 GHz.	11 12 12 12 13 13
6	5.2 5.3 5.4 5.5 5.6 5.7 EX	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ KHIBIT A – FCC PRODUCT LABEL INFORMATION	11 12 12 12 13 13 13
6	5.2 5.3 5.4 5.5 5.6 5.7 EX 6.1	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ KHIBIT A – FCC PRODUCT LABEL INFORMATION PROPOSED FCC ID LABEL	 11 12 12 13 13 14 14
Ū	5.2 5.3 5.4 5.5 5.6 5.7 EX 6.1 6.2	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ KHIBIT A – FCC PRODUCT LABEL INFORMATION PROPOSED FCC ID LABEL PROPOSED LABEL LOCATION ON EUT	11 12 12 13 13 13 14 14 14
6 7	5.2 5.3 5.4 5.5 5.6 5.7 EX 6.1 6.2	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ KHIBIT A – FCC PRODUCT LABEL INFORMATION PROPOSED FCC ID LABEL PROPOSED FCC ID LABEL PROPOSED LABEL LOCATION ON EUT KHIBIT B TEST SETUP PHOTOGRAPHS	 11 12 12 13 13 14 14 14 15
÷	5.2 5.3 5.4 5.5 5.6 5.7 EX 6.1 6.2 EX 7.1	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ KHIBIT A – FCC PRODUCT LABEL INFORMATION PROPOSED FCC ID LABEL PROPOSED FCC ID LABEL PROPOSED LABEL LOCATION ON EUT KHIBIT B TEST SETUP PHOTOGRAPHS CONDUCTED EMISSION-FRONT VIEW.	11 12 12 12 13 13 13 14 14 14 15 15
÷	5.2 5.3 5.4 5.5 5.6 5.7 EX 6.1 6.2 EX 7.1 7.2	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ KHIBIT A – FCC PRODUCT LABEL INFORMATION PROPOSED FCC ID LABEL PROPOSED FCC ID LABEL PROPOSED LABEL LOCATION ON EUT KHIBIT B TEST SETUP PHOTOGRAPHS CONDUCTED EMISSION-FRONT VIEW CONDUCTED EMISSION-FRONT VIEW	11 12 12 12 13 13 13 14 14 14 14 15 15
÷	5.2 5.3 5.4 5.5 5.6 5.7 EX 6.1 6.2 EX 7.1 7.2 7.3	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ KHIBIT A – FCC PRODUCT LABEL INFORMATION PROPOSED FCC ID LABEL PROPOSED FCC ID LABEL PROPOSED LABEL LOCATION ON EUT KHIBIT B TEST SETUP PHOTOGRAPHS CONDUCTED EMISSION-FRONT VIEW CONDUCTED EMISSION-FRONT VIEW RADIATED EMISSION-FRONT VIEW	11 12 12 13 13 13 14 14 14 14 15 15 15
÷	5.2 5.3 5.4 5.5 5.6 5.7 EX 6.1 6.2 EX 7.1 7.2 7.3 7.4	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ. XHIBIT A – FCC PRODUCT LABEL INFORMATION PROPOSED FCC ID LABEL PROPOSED FCC ID LABEL PROPOSED LABEL LOCATION ON EUT XHIBIT B TEST SETUP PHOTOGRAPHS CONDUCTED EMISSION-FRONT VIEW CONDUCTED EMISSION-FRONT VIEW RADIATED EMISSION-FRONT VIEW RADIATED EMISSION-REAR VIEW	11 12 12 12 13 13 13 14 14 14 15 15 16 16
÷	5.2 5.3 5.4 5.5 5.6 5.7 EX 6.1 6.2 EX 7.1 7.2 7.3 7.4	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ KHIBIT A – FCC PRODUCT LABEL INFORMATION PROPOSED FCC ID LABEL PROPOSED FCC ID LABEL PROPOSED LABEL LOCATION ON EUT KHIBIT B TEST SETUP PHOTOGRAPHS CONDUCTED EMISSION-FRONT VIEW CONDUCTED EMISSION-FRONT VIEW RADIATED EMISSION-FRONT VIEW	11 12 12 12 13 13 13 14 14 14 15 15 16 16
7	5.2 5.3 5.4 5.5 5.6 5.7 EX 6.1 6.2 EX 7.1 7.2 7.3 7.4 EX 8.1	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ	11 12 12 12 13 13 14 14 14 15 15 16 16 17 17
7	5.2 5.3 5.4 5.5 5.6 5.7 EX 6.1 6.2 EX 7.1 7.2 7.3 7.4 EX 8.1 8.2	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ KHIBIT A – FCC PRODUCT LABEL INFORMATION PROPOSED FCC ID LABEL PROPOSED FCC ID LABEL PROPOSED LABEL LOCATION ON EUT KHIBIT B TEST SETUP PHOTOGRAPHS CONDUCTED EMISSION-FRONT VIEW CONDUCTED EMISSION-FRONT VIEW RADIATED EMISSION-FRONT VIEW RADIATED EMISSION-REAR VIEW KHIBIT C EUT PHOTOGRAPHS EUT FRONT VIEW EUT FRONT VIEW EUT FRONT VIEW EUT FRONT VIEW	11 12 12 12 13 13 14 14 14 15 15 16 16 17 17 17
7	5.2 5.3 5.4 5.5 5.6 5.7 EX 6.1 6.2 EX 7.1 7.2 7.3 7.4 EX 8.1 8.2 8.3	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHz TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ CHIBIT A – FCC PRODUCT LABEL INFORMATION PROPOSED FCC ID LABEL PROPOSED FCC ID LABEL PROPOSED LABEL LOCATION ON EUT CONDUCTED EMISSION-FRONT VIEW CONDUCTED EMISSION-FRONT VIEW RADIATED EMISSION-FRONT VIEW RADIATED EMISSION-REAR VIEW CHIBIT C EUT PHOTOGRAPHS EUT FRONT VIEW EUT FRONT VIEW EUT FRONT VIEW EUT REAR VIEW EUT REAR VIEW EUT REAR COVER OFF VIEW	11 12 12 13 13 14 14 14 15 15 16 16 16 17 17 17 18
7	5.2 5.3 5.4 5.5 5.6 5.7 EX 6.1 6.2 EX 7.1 7.2 7.3 7.4 EX 8.1 8.2 8.3 8.4	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ CHIBIT A – FCC PRODUCT LABEL INFORMATION PROPOSED FCC ID LABEL PROPOSED FCC ID LABEL PROPOSED LABEL LOCATION ON EUT CONDUCTED EMISSION-FRONT VIEW CONDUCTED EMISSION-FRONT VIEW CONDUCTED EMISSION-FRONT VIEW RADIATED EMISSION-FRONT VIEW RADIATED EMISSION-FRONT VIEW EUT FRONT VIEW EUT FRONT VIEW EUT FRONT VIEW EUT REAR VIEW EUT REAR COVER OFF VIEW EUT REAR COVER OFF VIEW EUT REAR COVER OFF VIEW	11 12 12 13 13 14 14 14 14 15 15 16 16 16 17 17 17 18 18
7	5.2 5.3 5.4 5.5 5.6 5.7 EX 6.1 6.2 EX 7.1 7.2 7.3 7.4 EX 8.1 8.2 8.3	TEST SETUP TEST EQUIPMENT LIST AND DETAILS TEST PROCEDURE ENVIRONMENTAL CONDITIONS CORRECTED AMPLITUDE & MARGIN CALCULATION SUMMARY OF TEST RESULTS – 30 MHz TO 1 GHZ SUMMARY OF TEST RESULTS – 30 MHZ TO 1 GHZ CHIBIT A – FCC PRODUCT LABEL INFORMATION PROPOSED FCC ID LABEL PROPOSED FCC ID LABEL PROPOSED LABEL LOCATION ON EUT CONDUCTED EMISSION-FRONT VIEW CONDUCTED EMISSION-FRONT VIEW RADIATED EMISSION-FRONT VIEW RADIATED EMISSION-REAR VIEW CHIBIT C EUT PHOTOGRAPHS EUT FRONT VIEW EUT FRONT VIEW EUT FRONT VIEW EUT REAR VIEW EUT REAR VIEW EUT REAR COVER OFF VIEW	11 12 12 12 13 13 14 14 14 15 15 16 16 17 17 18 18 19

1 GENERAL DESCRIPTION

1.1 Product Description for Equipment under Test (EUT)

The ZTE Corporation's product, FCC ID: Q78-ZTEC321 or the "EUT" as referred to in this report is a 800MHz CDMA 1X Digital Mobile Phone, which measures approximately107mm(L)*45mm(W)*17.5 mm(H).

The frequency range is UL 824~849 MHz, DL 869~894 MHz.

1.2 EUT Photo



Additional Photos in Exhibit C

1.3 Objective

This report has been prepared by ZTE Corp. in accordance with Part 2, Subpart J, and Part 15, Subparts A and B of the Federal Communications Commission rules, and Canadian ICES-003, Interference – Causing Equipment Standards for Digital Apparatus.

The objective is to determine compliance with FCC Part 15 Standard, Class B limits, and Canadian ICES-003 Standard, Class B limits for conducted and radiated emission requirements for the digital device portion of this device. For all measurement and tests pertaining to the intentional radiator please see ZTE report RZTE0805213.

1.4 Related Submittal(s)/Grant(s)

There is on related original submittal under the same FCC ID, for the intentional radiator portion of the EUT subject to the FCC part 22H requirements. Please see ZTE report RZTE0805213 for measurement and testing results.

1.5 Test Methodology

All measurements contained in this report were conducted in accordance with ANSI C63.4-2003, American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the range of 9 kHz to 40 GHz.

All radiated and conducted emissions measurements were performed at ZTE Corporation Reliability Testing Center

1.6 Test Facility

ZTE Corporation Reliability Testing Center

ZTE Plaza, Keji Road South, Hi-Tech Industrial Park, NanShan District, Shenzhen, Guangdong, 518057, P.R. of China

Tel: +86-755-26770345 Fax: +86-755-26770347

Test site at ZTE Corporation has been fully described in reports submitted to the Federal Communication Commission (FCC).

The details of these reports have been found to be in compliance with the requirements of Section 2.948 of the FCC Rules on December 25, 2005. ZTE Corporation Lab's FCC Registration Number is 373926.

ZTE中兴 ZTE Corporation

2 SYSTEM TEST CONFIGURATION

2.1 Justification

The EUT was configured for testing according to ANSI C63.4-2003.

The final qualification test was performed with the EUT operating at normal mode.

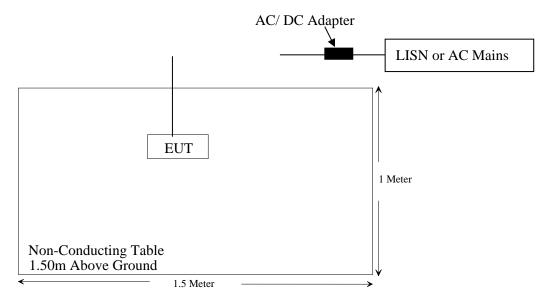
2.2 Equipment Modifications

No modifications were made to the EUT.

2.3 Local Support Equipment List and Details

Manufacturer	Equipment Description	Model	Serial Number	
Agilent	Wireless communication test set	8960 E5515C	GB42431673	

2.4 Test Setup Block Diagram



3 SUMMARY OF TEST RESULTS

Standard	Description	Result
FCC §15.107	Conducted Emission	Compliant
FCC §15.109	Radiated Emission	Compliant

4 FCC §15.107 - CONDUCTED EMISSIONS

4.1 Applicable Standard

4.1.1 As per FCC §15.107: Conducted Limits

(a) Except for Class A digital devices, for equipment that is designed to be connected to the public utility (AC) power line, the radio frequency voltage that is conducted back onto the AC power line on any frequency or frequencies within the band 150 kHz to 30 MHz shall not exceed the limits in the following table, as measured using a 50 μ H/50 ohms line impedance stabilization network (LISN). Compliance with the provisions of this paragraph shall be based on the measurement of the radio frequency voltage between each power line and ground at the power terminal. The lower limit applies at the band edges.

Frequency of Emission	Conducted Limit (dBµV)		
(MHz)	Quasi-peak	Average	
0.15-0.5	66 to 56*	56 to 46*	
0.5-5	56	46	
5-30	60	50	

*Decreases with the logarithm of the frequency.

4.2 EUT Setup

The conducted emissions tests were performed in the 10-meter test chamber, using the setup in accordance with ANSI C63.4-2003 measurement procedures. The specifications used were in accordance with FCC Part 15 Standard, Class B limits.

The spacing between the peripherals was 10 cm.

The external I/O cables were draped along the test table and bundled as required.

The EUT was connected the AC/DC adaptor which connected to the 120V/60Hz power source.

Manufacturer	Equipment Description	Model	Serial Number	Cal. Date
R&S	EMI Test Receiver 9kHz~2.75GHz	ESCS30	100068	2007-10-18
EMCO	LISN	4825/2	100022	2007-10-18
R&S	Pulse limiter 9kHz~30MHz	ESH3-Z2	100063	2007-10-18
	Cable	CE Cable	N/A	N/A

4.3 Test Equipment List and Details

• Statement of Traceability: ZTE Corporation Reliability Testing Center attests that all calibrations have been performed per the NVLAP requirements, traceable to the NIST.

4.4 Test Procedure

During the conducted emissions test, the power cord of the host system was connected to the main outlet of the LISN-1.

Maximizing procedure was performed on the six (6) highest emission readings from the EUT.

All data was recorded in the peak detection mode, quasi-peak and average. Average readings are labeled "AV," and Quasi-peak readings are labeled "QP," in the test data hereinafter.

4.5 Environmental Conditions

Temperature:	22° C
Relative Humidity:	55%
ATM Pressure:	1018mbar

*Testing was performed by Guan Bin on 2008-05-15

ZTE Corporation

4.6 Summary of Test Results

According to the recorded data, <u>the EUT complied with FCC §15.107 Standard</u>, <u>Class B limits</u>, and had the worst margin reading of:

Connection: 120 V/60 Hz AC						
Margin (dB)	Frequency (MHz)	Conductor Mode (Hot/Neutral)	Range (MHz)			
-13.5	0.387896	Hot	0.150 to 30 MHz			

Measurement Results: Quasi-Peak Detector

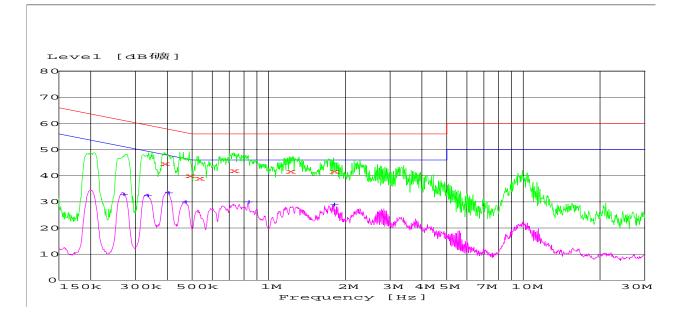
Frequency (MHz)	Level (dBµV)	Transd (dB)	Limit (dBµV)	Margin (dB)	Line	PE
0.387896	44.50	9.9	58	13.5	L1	FLO
0.725952	42.00	9.9	56	14.0	L1	FLO
1.210105	41.70	9.9	56	14.3	L1	FLO
1.796638	41.80	9.9	56	14.2	L1	FLO
1.300259	41.80	9.9	56	14.2	Ν	FLO

Measurement Results: Average Detector

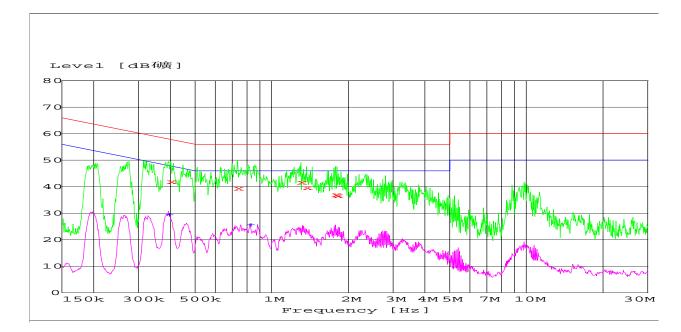
Frequency (MHz)	Level (dBµV)	Transd (dB)	Limit (dBµV)	Margin (dB)	Line	PE
0.331971	32.50	9.9	49	16.9	L1	FLO
0.402085	33.50	9.9	48	14.4	L1	FLO
0.828172	30.00	9.9	46	16.0	L1	FLO
1.796638	29.10	9.9	46	16.9	L1	FLO

4.7 Conducted Emissions Test Plots

120 V, 60 Hz - Line



120 V, 60 Hz – Neutral



5 FCC §15.109 – RADIATED EMISSIONS

5.1 Applicable Standard

As per FCC §15.109: Radiated Emission Limits

(a) Except for Class A digital devices, the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency of Emission (MHz)	Field Strength (µV/m)
30-88	100
88-216	150
216-960	200
Above 960	500

(g) As an alternative to the radiated emission limits shown in paragraphs (a) and (b) of this section, digital devices may be shown to comply with the standards contained in Third Edition of the International Special Committee on Radio Interference (CISPR), Pub. 22, "Information Technology Equipment – Radio Disturbance Characteristics – Limits and Methods of Measurement."

Note: The CISPR 22 §6 Standard, Class B limits are applied to the test data hereinafter.

5.2 Test Setup

The radiated emissions tests were performed in the 10-meter test chamber, using the setup in accordance with ANSI C63.4-2003 measurement procedures. The specifications used were in accordance with CISPR 22 Standard, Class B limits for frequencies between 30 MHz and 1 GHz, and FCC Part 15 Standard, Class B limits for frequencies above 1 GHz.

The spacing between the peripherals was 10 cm.

The external I/O cables were draped along the test table and bundled as required.

The EUT was connected to the AC/DC adaptor which connected to the 120V/60Hz power source.

Manufacturer	Equipment Description	Model	Serial Number	Calibration Date
R&S	EMI Test Receiver 20Hz~26.5GHz	ESI26	100058	2007-10-25
R&S	Log periodic Antenna 30~3000MHz	HL562	100022	2008-3-7
R&S	Cable Set Up to 18GHz	RF Cable	N/A	2007-10-25
Albatross	Anechoic Chamber 3m site	3m site	N/A	2008-5-14
R&S	Software	ES-K1	N/A	N/A
Agilent	Universal radio communication tester	8960	GB42431673	2008-01-18

5.3 Test Equipment List and Details

* Statement of Traceability: ZTE Corporation Reliability Testing Center attests that all calibrations have been performed per the NVLAP requirements, traceable to the NIST.

5.4 Test Procedure

The test site semi-anechoic chamber has met the requirement of NSA tolerance 4dB according to the standards: ANSI C63.4 (2003). The test distance was 3m. The EUT was set-up on insulator 0.8m above the Metallic Turntable

The radiated disturbance measurements were made using a Rohde and Schwarz ESI Test Receiver and control software ES-K1.

A preliminary scan and a final scan of the emissions were made form 30MHz to 1GHz by using test script of software; the emissions were measurement using a Quasi-Peak detector. The maximal emission value was acquired by adjusting the antenna height, polarization and turntable azimuth in accordance with the software setup. Normally, the height range of antenna was 1m to 4m, the azimuth range of turntable was 0°to 360°. The receive antenna has two polarizations V and H.

Measurement bandwidth (RBW) for 30 MHz to 1000 MHz: 120 kHz.

5.5 Environmental Conditions

Temperature:	22.5° C		
Relative Humidity:	57%		
ATM Pressure:	1016mbar		

*Testing was performed by Guan bin on 2008-05-15

5.6 Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor, and Cable Factor, and subtracting the Amplifier Gain from the Amplitude reading. The basic equation is as follows:

Corrected Amplitude = Indicated Reading + Antenna Factor + Cable Factor - Amplifier Gain

The "**Margin**" column of the following data tables indicates the degree of compliance within the applicable limit. For example, a margin of -7 dB means the emission is 7 dB below the maximum limit for Class B. The equation for margin calculation is as follows:

Margin = Corrected Amplitude - Class B Limit

5.7 Summary of Test Results – 30 MHz to 1 GHz

According to the recorded data, <u>the EUT complied with FCC §15.109 Standard</u>, <u>Class B limits</u>, and had the worst margin readings – when calculated using CISPR 22 Standard, Class B limits – of:

Margin	Frequency	Polarization	Range	
(dB)	(MHz)	(Horizontal/Vertical)	(MHz)	
-2.0	47.494990	Vertical		

Frequency (MHz)	Level (dBµV/m)	Azimuth deg	Ant. Height (cm)	Ant. Polar (V/H)	Transd (dB)	Limit (dBµV/m)	Margin (dB)
31.482966	36.43	296.00	100.0	Vertical	-6.3	40.0	3.6
47.494990	37.99	24.00	100.0	Vertical	-15.1	40.0	2.0
55.270541	30.93	52.00	100.0	Vertical	-20.0	40.0	9.1
852.264529	40.01	261.00	100.0	Vertical	0.3	46.0	6.0
854.208417	41.45	115.00	100.0	HOR	0.3	46.0	4.6

Measurement Results: Quasi-Peak Detector